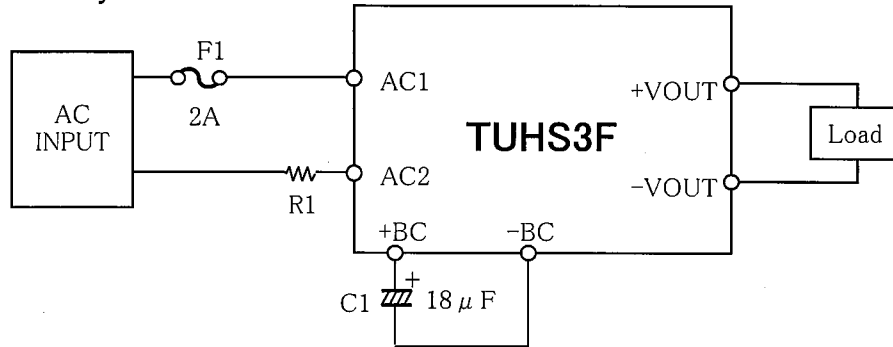


Approved: Kenji Shiho
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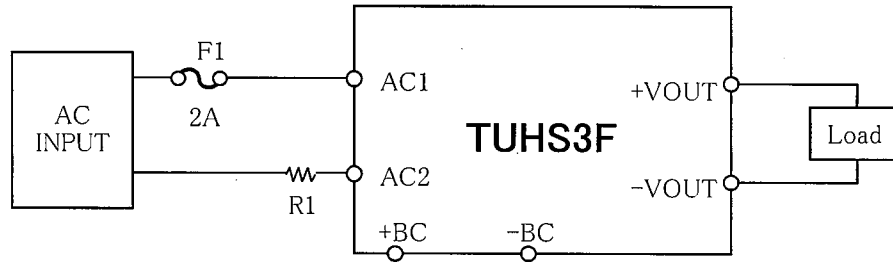
No.	Test item	Test conditions	Conditions of acceptability	Result
1	High temp./overload test	(1) Input Rated input AC100V,200V (2) Output Overload (3) Ambient temp. 85°C (4) Test period 48 hours (5) Testing circuitry Fig.1	(1) Power supply is not failed.	ok
2	No ventilation test	(1) Input Rated input AC100,200V (2) Output Rated output (3) Ambient temp. 25±10°C (4) Test period 48 hours (5) Testing circuitry Fig.1	(1) No smoke, no fire.	ok
3	Capacitance reduction test	(1) Input Rated input AC100V,200V (2) Output Rated output (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.2	(1) No smoke, no fire. (2) No rise of the output voltage.	ok
4	Low voltage input test	(1) Input Min. regulation voltage (2) Output Rated output (3) Ambient temp. 25±10°C (4) Test period 48 hours (5) Testing circuitry Fig.1	(1) Power supply is not failed.	ok
5	Input ON/OFF test	(1) Input Max.voltage AC264V T= 2sec Duty= 50% (2) Output Rated output (3) Ambient temp. 85°C (4) On/off period 1,000 (5) Testing circuitry Fig.1	(1)Power supply is not failed. (2)The surge current of each components should not exceed the rated value.	ok
6	Output ON/OFF test	(1) Input Rated input AC200V (2) Output 0%←→100% T= 2sec Duty= 50% (3) Ambient temp. 25±10°C (4) On/off period 1,000 (5) Testing circuitry Fig.1	(1) Power supply is not failed.	ok
7	Output-short start test	(1) Input Max.volotage AC264V (2) Output Short start (3) Ambient temp. 25±10°C (4) Testing circuitry Fig.1	(1) Power supply is not failed.	ok
8	Output short test	(1) Input Rated input AC100V,200V (2) Output Short (3) Ambient temp. 25±10°C (4) Test period 48 hours (5) Testing circuitry Fig.1	(1) Power supply is not failed.	ok
9	Withstand voltage test (High-pot test)	(1) Input Not applied. (2) Ambient temp. 25±10°C (3) The applied voltage is 1.4 times of specifications.	(1) Insulation breakdown ,flashover or electric arc is not occurred.	ok
10	Isolation resistance test	(1) Input Not applied. (2) Ambient temp. 25±10°C	(1) When a regulation voltage is applied, isolation resistance is 1.4 times of specifications.	ok
11	Vibration/impact test	Vibration (1)F=10~55Hz 49.0m/s ² (5.0G) (2)3 minutes period (3)60 minutes along X, Y and Z axis Impact (1)196.1m/s ² (20G) 11ms (2)Once each X, Y and Z axis	(1) No degradation of electric characteristics after test. (2) No crack at solder joint. (3) No marked damage of appearance.	ok
12	Line Noise Tolerance test	(1) Input AC230V (2) Output Rated output (3) Ambient temp. 25±10°C (4) Test Voltage ±3 kV (5) Pulse width 50~1000ns (6) Mode Normal (7) Testing circuitry Fig.3	(1) No protection circuit failure. (2) No output voltage drop with control circuit failure. (3) No any other function failure.	ok

○ Testing circuitry



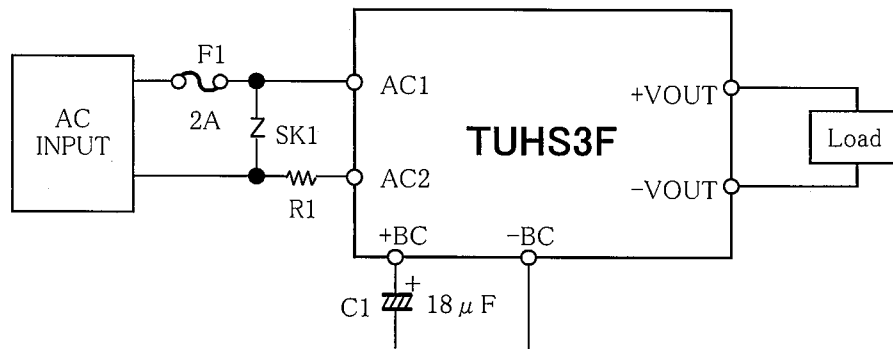
F1: SLT250V2A (Nippon Seisen) 2A
 R1: F1K100J14 (TAMURA THERMAL DEVICE) 10Ω

Fig.1 Testing circuitry



F1: SLT250V2A (Nippon Seisen) 2A
 R1: F1K100J14 (TAMURA THERMAL DEVICE) 10Ω

Fig.2 Testing circuitry



F1: SLT250V2A (Nippon Seisen) 2A
 R1: F1K100J14 (TAMURA THERMAL DEVICE) 10Ω
 SK1: TND10V-511K (NIPPON CHEMI-CON)

Fig.3 Testing circuitry